
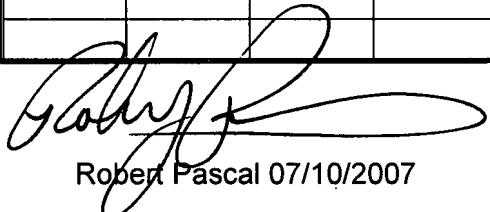


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/537,470	YANO ET AL.	
	Examiner	Art Unit	
	Hieu P. Nguyen	2817	

ISSUE CLASSIFICATION										
ORIGINAL					CROSS REFERENCE(S)					
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
330		384			330	302				
INTERNATIONAL CLASSIFICATION										
H	0	3	G	3/30						
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				/						
				/						

Hieu Nguyen 07/10/2007 (Assistant Examiner) (Date)		 Robert Pascal 07/10/2007 (Primary Examiner) (Date)	Total Claims Allowed: 4	
(Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant					<input type="checkbox"/> CPA					<input type="checkbox"/> T.D.					<input type="checkbox"/> R.1.47				
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